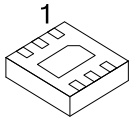
UTT7N03M

POWER MOSFET

7A, 30V N-CHANNEL ENHANCEMENT MODE TRENCH POWER MOSFET



DFN2020-6

■ DESCRIPTION

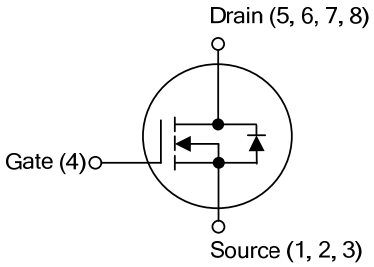
The UTC **UTT7N03M** is a N-channel Power MOSFET, it uses UTC's advanced technology to provide the customers with low Rdson characteristic by high cell density trench technology.

The UTC **UTT7N03M** is suitable for high efficiency synchronous rectification in SMPS, UPS, hard switched and high frequency circuits.

■ FEATURES

* $R_{DS(ON)}$ ≤ 30 mΩ @ V_{GS}=10V, I_D=7.0A
  $R_{DS(ON)}$ ≤ 40 mΩ @ V_{GS}=4.5V, I_D=7.0A
* High Cell Density Trench Technology
* High Power and Current Handling Capability

■ SYMBOL



■ ORDERING INFORMATION

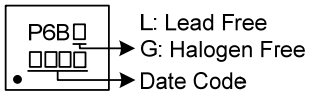
Ordering Number		Package	Pin Assignment						Packing
Lead Free	Halogen Free		1	2	3	4	5	6	
UTT7N03ML-K06-2020-R	UTT7N03MG-K06-2020-R	DFN2020-6	D	D	G	D	D	S	Tape Reel

Note: Pin Assignment: G: Gate D: Drain S: Source

UTT7N03MG-K06-2020-R

(1)Packing Type	(1) R: Tape Reel
(2)Package Type	(2) K06-2020: DFN2020-6
(3)Green Package	(3) G: Halogen Free and Lead Free, L: Lead Free

■ MARKING



■ ABSOLUTE MAXIMUM RATING (T_C=25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	30	V
Gate-Source Voltage		V_{GSS}	±20	V
Drain Current	Continuous	I_D	7	A
	Pulsed (Note 2)	I_{DM}	28	A
Avalanche Energy (Note 3)	Single Pulsed (Note 3)	E_{AS}	6	mJ
Peak Diode Recovery dv/dt (Note 4)		dv/dt	1.8	V/ns
Power Dissipation		P_D	1.6	W
Junction Temperature		T_J	+150	°C
Storage Temperature Range		T_{STG}	-55 ~ +150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.
2. Repetitive Rating: Pulse width limited by maximum junction temperature.
3. L =0.1 mH, I_{AS} = 11A, V_{DD} = 25V, R_G = 25Ω, Starting T_J = 25°C.
4. I_{SD} ≤ 7.0A, di/dt ≤ 200A/μs, V_{DD} ≤ $V_{(BR)DSS}$, T_J = 25°C.

■ THERMAL RESISTANCES CHARACTERISTICS

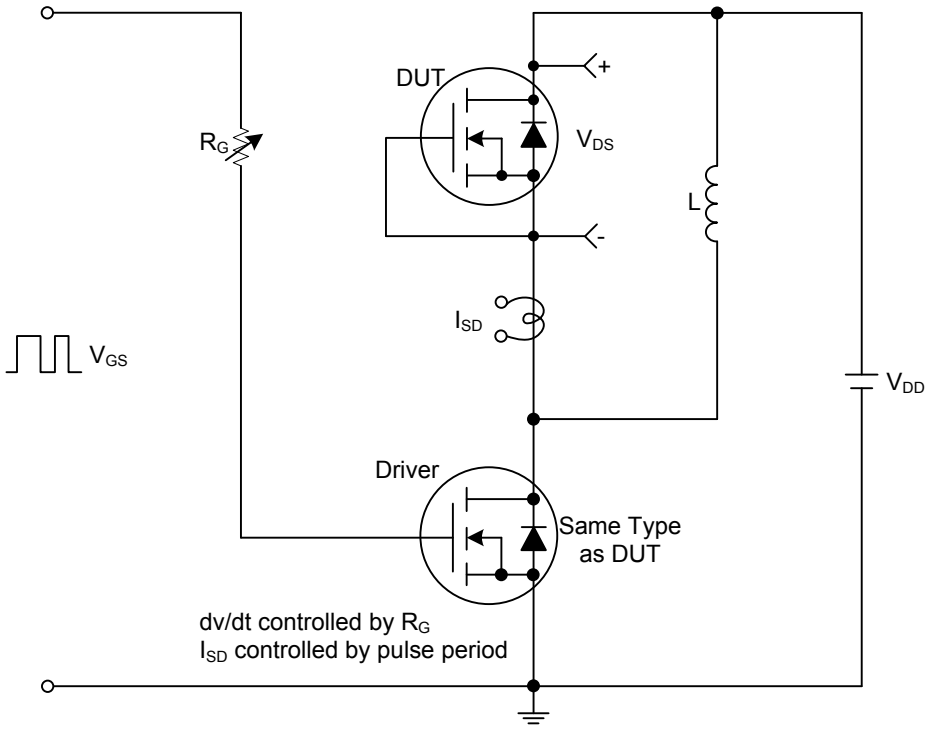
PARAMETER	SYMBOL	RATINGS	UNIT
Junction to Ambient	θ_{JA}	75	°C/W
Junction to Case	θ_{JC}	2.6	°C/W

■ ELECTRICAL CHARACTERISTICS (T_J =25°C, unless otherwise specified)

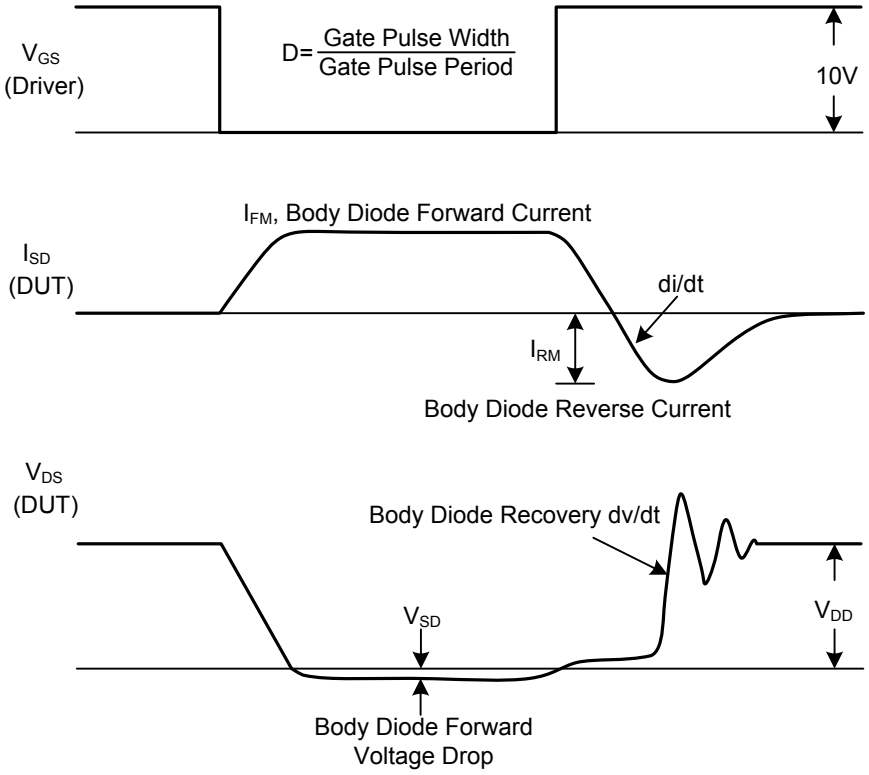
PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage		BV_{DSS}	I_D=250μA, V_{GS}=0V	30			V
Drain-Source Leakage Current		I_{DSS}	V_{DS}=30V, V_{GS}=0V			1.0	μA
Gate-Source Leakage Current	Forward	I_{GSS}	V_{GS}=+20V, V_{DS}=0V			+100	nA
	Reverse		V_{GS}=-20V, V_{DS}=0V			-100	nA
ON CHARACTERISTICS							
Gate Threshold Voltage		$V_{GS(TH)}$	V_{DS}=V_{GS}, I_D=250μA	1.0		3.0	V
Static Drain-Source On-State Resistance		$R_{DS(ON)}$	V_{GS}=10V, I_D=7.0A			30	mΩ
			V_{GS}=4.5V, I_D=7.0A			40	mΩ
DYNAMIC PARAMETERS							
Input Capacitance		C_{ISS}	V_{GS}=0V, V_{DS}=15V, f=1.0MHz		343		pF
Output Capacitance		C_{OSS}			74		pF
Reverse Transfer Capacitance		C_{RSS}			50		pF
SWITCHING PARAMETERS							
Total Gate Charge (Note 1)		Q_G	V_{DS}=24V, V_{GS}=10V, I_D=7.0A, I_G=1mA (Note 1, 2)		12		nC
Gate to Source Charge		Q_{GS}			1.7		nC
Gate to Drain Charge		Q_{GD}			3.5		nC
Turn-on Delay Time (Note 1)		$t_{D(ON)}$	V_{DS}=15V, V_{GS}=10V, I_D=7.0A, R_G=25Ω (Note 1, 2)		9.6		ns
Rise Time		t_R			8.0		ns
Turn-off Delay Time		$t_{D(OFF)}$			29		ns
Fall-Time		t_F			21		ns
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS							
Maximum Body-Diode Continuous Current		I_S				7.0	A
Maximum Body-Diode Pulsed Current		I_{SM}				28	A
Drain-Source Diode Forward Voltage (Note 1)		V_{SD}	I_S=7.0A, V_{GS}=0V			1.2	V
Reverse Recovery Time (Note 1)		t_{rr}	I_S=7.0A, V_{GS}=0V, dI_F/dt =100A/μs		250		nS
Reverse Recovery Charge		Q_{rr}			275		nC

Notes: 1. Pulse Test : Pulse width ≤ 300μs, Duty cycle ≤ 2%.
2. Essentially independent of operating ambient temperature.

■ TEST CIRCUITS AND WAVEFORMS



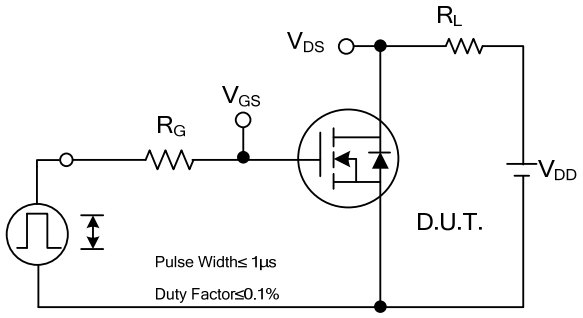
Peak Diode Recovery dv/dt Test Circuit



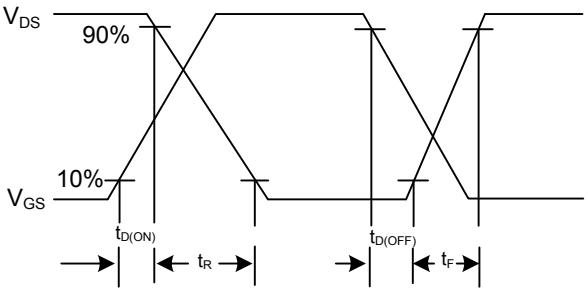
Peak Diode Recovery dv/dt Test Circuit and Waveforms

Peak Diode Recovery dv/dt Waveforms

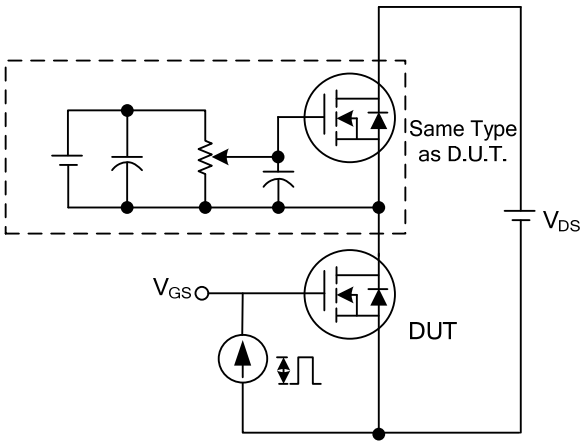
■ TEST CIRCUITS AND WAVEFORMS



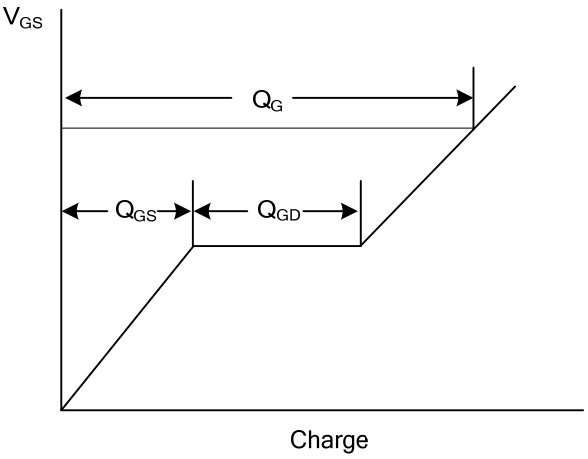
Switching Test Circuit



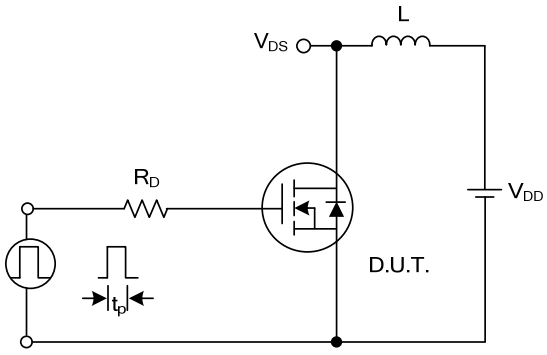
Switching Waveforms



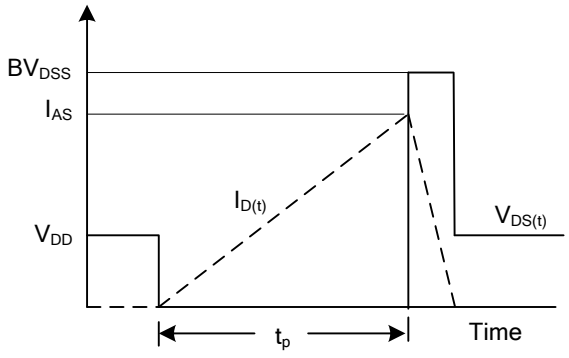
Gate Charge Test Circuit



Gate Charge Waveform



Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms

■ TYPICAL CHARACTERISTICS